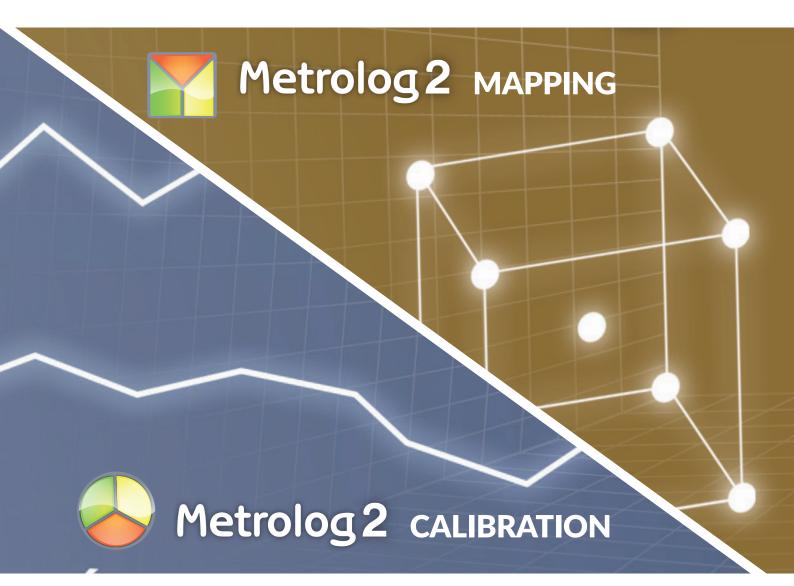
Measurement, monitoring and metrology





# **METROLOGY SOFTWARE**

# **TO PERFORM CALIBRATION AND MAPPING**

During all steps of the procedure and until certificate edition

www.jri-corp.com

# Software designed to internalise and simplify your metrology operations

Designed to meet the needs of our customers having the required means to realize metrology operations, the Metrolog Calibration and Mapping software are also use by the JRI metrologists in laboratory and on site.

Metrolog 2 Calibration



Compliance judgment of your measuring chains and your chamber performances

Complete process management until the edition of the customized report with one single software

Ability to produce metrology

service in case of Quality audits

Compliance upgrade with the current standands

Calibrate, check, gauge and adjust all type of measuring chains

Measuring chains management

Map and check climatic chambers according to FDX 15-140 and CEI 60068 3-5/3-11 standards

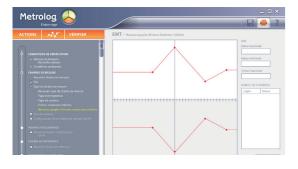
• Up to 6 temperature mappings simultaneously

• Data display during the mapping to check proceeding

• Change of the measuring interval during the mapping to be able to manage events as door openings, network failures ...

• Easy cabinet management by listing the completed certificates with their numbers and dates, the events (e.g. maintenance operations, etc..)

• Import data from other brand recorders in .csv format



• Manage the measuring chains fleet with display of

• Automate calibration through automatic detection

• Compliance with NFX 07-012 and NFX 07-011 standards related to the calibration certificates and

metrology operations history

of stability steps

checking reports

Maximum permissible errors (MPE) management



- Consideration of the MPE in your different measuring chains systems as well as correction and calibration uncertainties of the standard reference probe
- Use of several reference standards or calibration environments to perform a metrology operation

|                      | Metrolog |              |        |  |  |                   |                             |  |                     |
|----------------------|----------|--------------|--------|--|--|-------------------|-----------------------------|--|---------------------|
| INFIGURATION         |          |              |        | CHAÎNE DE RÉFÉRENCE                            |  |                   |                             |  |                     |
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**Reference standard configuration** 



with step by step procedure

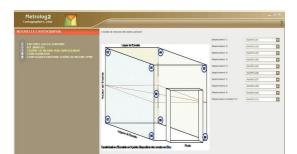
# Customise your calibration kit or mapping kit

Choose the quantity of Nano SPY or LoRa SPY recorders you need and add the suitable Metrolog 2 software!



# **Metrolog 2 Mapping**

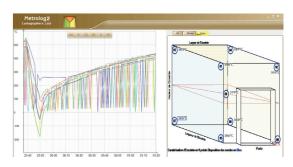




### Measuring chains positioning



### **Parameters configuration**



Graph of the temperature data

## Our reference devices for calibration operations

The Nano SPY Reference and LoRa SPY Reference models are designed to perform calibration of the recorders of their respective ranges. They measure with high accuracy and record temperature.

| Nano SPY Reference<br>Reference device to perform<br>Nano SPY recorders calibration                           | Measurement range : -196°C to +150°C<br>Accuracy : $\pm 0.15$ °C from 0°C to +40 °C<br>$\pm 0.2$ °C from -30°C to 0°C and from +40°C to +150°C<br>$\pm 0.5$ °C out of these ranges<br>$\pm 0.6$ °C at -196°C |
|---|--|
| LoRa <sup>®</sup> SPY Reference<br>Reference device to perform<br>LoRa <sup>®</sup> SPY recorders calibration | Measurement range : -196°C to +150°C<br>Accuracy : $\pm 0,12$ °C from 0 to +50°C<br>$\pm 0,20$ °C from -30°C to 0°C and from +50°C to +150°C<br>$\pm 0,50$ °C out of these ranges                            |

## **Our training sessions**



The JRI Academy performs training sessions for all levels : monitoring systems, metrology and skills transfer.

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Our partners

LoRa Alliance Member



